

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Yeo, et al.

Attorney Docket: TSM03-0553

Filed:

September 22, 2003

Examiner:

Unknown

Serial No.:

10/667,871

Art Unit:

2811

For:

Resistor with Reduced Leakage

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Applicant wishes to bring to the attention of the Patent and Trademark Office the information noted on the enclosed form PTO/SB/08A & 08B that may be considered material to the examination of the above-identified application.

Cites A-P are being filed under the waived requirement of 37 CFR 1.98(a)(2)(i) dated July 11, 2003; therefore, copies of these U.S. patents are not included. Cites Q-X, non-U.S. patents, are attached.

No fee is due at this time, as this Information Disclosure Statement is being filed pursuant to 37 C.F.R. § 1.97(b)(1), within three months of the filing date of a national application other than a continued prosecution application under § 1.53(d).

Respectfully submitted,

December 22, 2003

Date

Attorney for Applicant

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PTO/SB/08A (05-03)
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S	ubstitute for form 1449	PA/PTO		Con	Complete if Known		
				Application Number	10/667,871		
	INFORMATIO	N DISCLO	DSURE	Filing Date	September 22, 2003		
	STATEMENT	BY APPL	ICANT.	First Named Inventor	Yeo, et al.		
				Art Unit_	2811		
	(use as many sh	eets as nece	essary)	Examiner Name	Unknown		
Sheet	1	of	2	Attorney Docket Number	TSM03-0553		

U.S. PATENT DOCUMENTS								
Examiner Initials*	Cite No.1	Document Number Number - Kind Code ^{2 (if known)}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevar Figures Appear			
	Α	US-4,314,269	02-02-1982	Fujiki				
	В	US-5,629,544	05-13-1997	Voldman, et al.				
	С	US-5,811,857	09-22-1998	Assaderaght, et al.				
	D	US-6,008,095	12-28-1999	Gardner, et al.				
	E	US-6,015,993	01-18-2000	Voldman, et al.				
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	G	US-6,258,664 B1	07-10-2001	Reinberg				
	Н	US-6,294,834 B1	09-25-2001	Yeh, et al.				
	l	US-6,358,791 B1	03-19-2002	Hsu, et al.				
	J	US-2002/0153549 A1	10-24-2002	Laibowitz, et al.				
	K	US-6,475,838 B1	11-05-2002	Bryant, et al.				
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	Р	US-6,558,998 B2	05-06-2003	Belleville, et al.				

		FOREIG	N PATENT DOCU	IMENTS		
Examiner Initials*		Foreign Patent Document	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
	Cite No. ¹	Country Code ³ - Number ⁴ - Kind Code ⁵ (<i>if known</i>)	MM-DD-YYYY	Applicant of Cited Document		
	Q	WO 03/017336 A2	02-27-2003	Amberwave Systems Corporation		

		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite ₁ No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	R	WANG, L.K., et al., "On-Chip Decoupling Capacitor Design to Reduce Switching-Noise-Induced Instability in CMOS/SOI VLSI," Proceedings of the 1995 IEEE International SOI Conference, Oct. 1995, pp. 100-101.	
	S	YEOH, J.C., et al., "MOS Gated Si:SiGe Quantum Wells Formed by Anodic Oxidation," Semicond. Sci. Technol. (1998), Vol. 13, pp. 1442-1445, IOP Publishing Ltd., UK.	
	Т	CAVASSILAS, N., et al., "Capacitance-Voltage Characteristics of Metal-Oxide-Strained Semiconductor Si/SiGe Heterostructures," Nanotech 2002, Vol. 1, pp. 600-603.	

Examiner	Date	
Signature	Considered	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 'Applicant's unique citation designation number (optional). 'See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. 'Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 'For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 'Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. 'Applicant is to place a check mark here if English language Translation is attached.

Translation is attached. This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Substitu	ute for form 1449B/PT	ТО		Complete if Known				
				Application Number	10/667,871			
II	NFORMATION [DISCLO	SURE	Filing Date	September 22, 2003			
	STATEMENT BY			First Named Inventor	Yeo, et al.			
	(use as many sheet	—		Group Art Unit	2811			
				Examiner Name	Unknown			
Sheet	2	of	2	Attorney Docket Number	TSM03-0553			

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OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS						
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	U	BLAAUW, D., et al., "Gate Oxide and Subthreshold Leakage Characterization, Analysis and Optimization," date unknown.				
	V	"Future Gate Stack," International Sematech, 2001 Annual Report.				
	W	CHANG, L., et al., "Reduction of Direct-Tunneling Gate Leakage Current in Double-Gate and Ultra-Thin Body MOSFETs," 2001 IEEE, Berkeley, CA.				
	х	CHANG, L., et al., "Direct-Tunneling Gate Leakage Current in Double-Gate and Ultrathin Body MOSFETs," 2002 IEEE, Vol. 49, No. 12, December 2002.				
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Examiner	Date		
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20231 EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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